



Image Processing: Machine Vision Applications VI

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Contents

vii Conference Committee

SESSION 1 SYSTEMS I

- 8661 02 **A polynomial phase-shift algorithm for high precision three-dimensional profilometry** [8661-1]
F. Deng, The Univ. of Hong Kong (Hong Kong, China) and ASM Pacific Technology Ltd. (Hong Kong, China); C. Liu, W. Sze, J. Deng, K. S. M. Fung, ASM Pacific Technology Ltd. (Hong Kong, China); E. Y. Lam, The Univ. of Hong Kong (Hong Kong, China)
- 8661 03 **High-temperature dual-band thermal imaging by means of high-speed CMOS camera system** [8661-2]
W. Hauer, G. Zauner, Univ. of Applied Sciences Upper Austria (Austria)
- 8661 04 **A state observer for using a slow camera as a sensor for fast control applications** [8661-3]
R. Gahleitner, M. Schagerl, Univ. of Applied Sciences Upper Austria (Austria)

SESSION 2 APPLICATIONS I

- 8661 05 **Multiple-level patch-based object tracking using MLBP-based integral histogram** [8661-4]
J. Yuan, K. Egiazarian, Tampere Univ. of Technology (Finland)
- 8661 06 **Periodicity estimation of nearly regular textures based on discrepancy norm** [8661-5]
G. Stübl, P. Haslinger, V. Wieser, Software Competence Ctr. Hagenberg (Austria); J. Scharinger, Johannes Kepler Univ. Linz (Austria); B. Moser, Software Competence Ctr. Hagenberg (Austria)
- 8661 07 **Gradient feature matching for in-plane rotation invariant face sketch recognition** [8661-6]
A. T. Alex, V. K. Asari, A. Mathew, The Univ. of Dayton (United States)
- 8661 08 **An iris segmentation algorithm based on edge orientation for off-angle iris recognition** [8661-7]
M. Karakaya, D. Barstow, H. Santos-Villalobos, C. Boehnen, Oak Ridge National Lab. (United States)

SESSION 3 ALGORITHMS I

- 8661 09 **Dense sampling of shape interiors for improved representation** [8661-8]
V. Premachandran, R. Kakarala, Nanyang Technological Univ. (Singapore)
- 8661 0A **Efficient defect detection with sign information of Walsh Hadamard transform** [8661-9]
Q. Zhang, Arizona State Univ. (United States); P. van Beek, Sharp Labs. of America, Inc. (United States); C. Yuan, Amazon (United States); X. Xu, Sharp Labs. of America, Inc. (United States); H. Seo, Qualcomm (United States); B. Li, Arizona State Univ. (United States)

- 8661 0B **Improving the performance of interest point detectors with contrast stretching functions** [8661-10]
P. K. Gunashekhar, B. K. Gunturk, Louisiana State Univ. (United States)
- 8661 0C **Object detection using feature-based template matching** [8661-11]
S. Bianco, M. Buzzelli, R. Schettini, Univ. degli Studi di Milano-Bicocca (Italy)

SESSION 4 SYSTEMS II

- 8661 0D **Touch sensing analysis using multi-modal acquisition system** [8661-12]
J. S. King, D. Pikula, Z. Baharav, Corning Inc. (United States)
- 8661 0F **Structural deformation measurement via efficient tensor polynomial calibrated electro-active glass targets** [8661-14]
C. Gugg, M. Harker, P. O'Leary, Montan Univ. Leoben (Austria)
- 8661 0G **Machine vision system for the control of tunnel boring machines** [8661-15]
M. Habacher, P. O'Leary, M. Harker, Montan Univ. Leoben (Austria); J. Golser, GEODATA Group (Austria)

SESSION 5 ALGORITHMS II

- 8661 0H **Eliminating illumination effects by discrete cosine transform (DCT) coefficients' attenuation and accentuation** [8661-16]
S. Du, IntelliView Technologies Inc. (Canada); M. Shehata, Benha Univ. (Egypt); W. Badawy, C. A. Rahman, IntelliView Technologies Inc. (Canada)
- 8661 0I **Non-rigid ultrasound image registration using generalized relaxation labeling process** [8661-17]
J.-H. Lee, Keimyung Univ. (Korea, Republic of); Y. K. Seong, M. Park, K.-G. Woo, Samsung Advanced Institute of Technology (Korea, Republic of); J. Ku, H.-J. Park, Keimyung Univ. (Korea, Republic of)
- 8661 0J **Mammogram CAD, hybrid registration and iconic analysis** [8661-18]
A. Boucher, F. Cloppet, N. Vincent, Univ. Paris Descartes (France)

SESSION 6 APPLICATIONS II

- 8661 0K **Neutron imaging for geothermal energy systems** [8661-19]
P. Bingham, Y. Polsky, L. Anovitz, Oak Ridge National Lab. (United States)
- 8661 0L **Wave front distortion based fluid flow imaging** [8661-20]
E. Iffa, W. Heidrich, The Univ. of British Columbia (Canada)
- 8661 0M **Autonomous ship classification using synthetic and real color images** [8661-21]
D. Kumlu, B. K. Jenkins, The Univ. of Southern California (United States)

- 8661 ON **Fast and flexible 3D object recognition solutions for machine vision applications** [8661-22]
I. Effenberger, J. Kühnle, A. Verl, Fraunhofer-Institut für Produktionstechnik und Automatisierung (Germany)

SESSION 7 ALGORITHMS III: PATTERN RECOGNITION

- 8661 0O **Low complexity smile detection technique for mobile devices** [8661-23]
V. Tomaselli, M. Guarnera, C. D. Marchisio, S. Moro, STMicroelectronics (Italy)
- 8661 0P **Density-induced oversampling for highly imbalanced datasets** [8661-24]
D. Fecker, V. Märgner, T. Fingscheidt, Technische Univ. Braunschweig (Germany)
- 8661 0Q **Coherent image layout using an adaptive visual vocabulary** [8661-25]
S. E. Dillard, M. J. Henry, S. Bohn, L. J. Gosink, Pacific Northwest National Lab. (United States)
- 8661 0R **Shape recognition for capacitive touch display** [8661-26]
I. Guarneri, A. Capra, STMicroelectronics (Italy); G. M. Farinella, S. Battiatto, Univ. degli Studi di Catania (Italy)

INTERACTIVE PAPER SESSION

- 8661 0S **An elliptic phase-shift algorithm for high speed three-dimensional profilometry** [8661-27]
F. Deng, The Univ. of Hong Kong (Hong Kong, China) and ASM Pacific Technology Ltd. (Hong Kong, China); Z. Li, Istituto Italiano di Tecnologia (Italy); J. Chen, Harbin Institute of Technology (China); J. Deng, K. S. M. Fung, ASM Pacific Technology Ltd. (Hong Kong, China); E. Y. Lam, The Univ. of Hong Kong (Hong Kong, China)
- 8661 0T **An incompressible fluid flow model with mutual information for MR image registration** [8661-29]
L. Tsai, H.-H. Chang, National Taiwan Univ. (Taiwan)
- 8661 0U **Improved skin detection method by iteratively eliminating pseudo-skin colors through combined skin filter** [8661-31]
O.-Y. Kwon, K.-A. Kim, S.-I. Chien, Kyungpook National Univ. (Korea, Republic of)
- 8661 0V **A modified hierarchical graph cut based video segmentation approach for high frame rate video** [8661-32]
X. Hu, Nanjing Univ. of Posts and Telecommunications (China); S. Chakravarty, New York Institute of Technology (China); Q. She, B. Wang, Nanjing Univ. of Posts and Telecommunications (China)
- 8661 0W **Power and execution performance tradeoffs of GPGPU computing: a case study employing stereo matching** [8661-33]
S. Arunagiri, J. Jaloma, R. Portillo, A. Argueta, The Univ. of Texas at El Paso (United States)
- 8661 0X **An efficient algorithm for food quality control based on multispectral signatures** [8661-34]
J. C. Valdiviezo-N., Univ. Politécnica de Tulancingo (Mexico); G. Urcid, Instituto Nacional de Astrofísica, Óptica y Electrónica (Mexico); C. Toxqui, A. Padilla, C. Santiago, Univ. Politécnica de Tulancingo (Mexico)

- 8661 0Y **Bottle inspector based on machine vision** [8661-35]
C. Toxqui-Quitl, J. Cardenas-Franco, A. Padilla-Vivanco, J. Valdiviezo-Navarro, Univ.
Politécnica de Tulancingo (Mexico)
- 8661 10 **Defect inspection technology for a gloss-coated surface using patterned illumination**
[8661-37]
T. Nagato, T. Fuse, T. Koezuka, Fujitsu Labs., Ltd. (Japan)
- 8661 12 **A semi-automatic annotation tool for cooking video** [8661-39]
S. Bianco, G. Ciocca, P. Napoletano, R. Schettini, Univ. degli Studi di Milano-Bicocca (Italy);
R. Margherita, AlmavivA S.p.A. (Italy); G. Marini, G. Gianforme, G. Pantaleo, Almawave
S.r.l. (Italy)
- 8661 13 **Intensity and color descriptors for texture classification** [8661-40]
C. Cusano, Univ. degli Studi di Pavia (Italy); P. Napoletano, R. Schettini, Univ. degli Studi di
Milano-Bicocca (Italy)

Author Index

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Session Chairs

- 1 Systems I
Philip R. Bingham, Oak Ridge National Laboratory (United States)
- 2 Applications I
Hamed Sari-Sarraf, Texas Tech University (United States)
- 3 Algorithms I
Edmund Y. Lam, The University of Hong Kong (Hong Kong, China)
- 4 Systems II
Kurt S. Niel, Fachhochschule Wels (Austria)
- 5 Algorithms II
Edmund Y. Lam, The University of Hong Kong (Hong Kong, China)
- 6 Applications II
Kurt S. Niel, Fachhochschule Wels (Austria)
- 7 Algorithms III: Pattern Recognition
Philip R. Bingham, Oak Ridge National Laboratory (United States)